

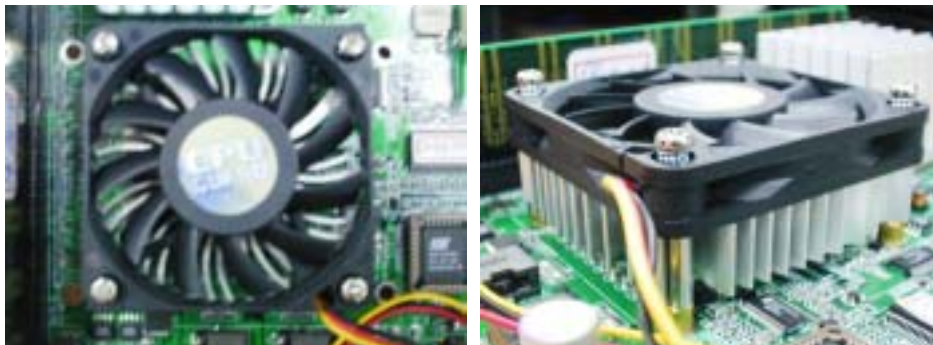


# Test item list

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Num	Item	Spec
1.	<b>Low Noise Medical Station:</b>	Onyx-153D
	1.LCD	15" CPT CLAA150XP03
	2.Power	EPD-146-3
	3. Inverter	HWA YOUN QF132V1.16
	4. Adapter	FSP105-AGB
2.	<b>CPU Board:</b>	PCM-8200 Rev: A1.0
	1. Bios Ver.	1.0
	2.CPU	Genuine Intel Mobile 1.6GHz
	3.Memory	DSL 512MB SAMSUNG K4H560838F-TCB3 (DDR-333)
	4.HDD	Fujitsu MHT2020AT 20GB
	5.DVD-ROM	TEAC DV-28SL

## CPU Cooler



# Temperature cycle test

**Test Date:** 11-08~11-2005

**Test Product:** Onyx-153D (PCM-8200 Rev: A1.0).

**Test Site:** AAEON QA Internal Lab.

**Performed By:** Rex Chang

**Test Standard:** Reference IEC68-2-14 Testing procedures  
Test N: Change of temperature Test

**Test Equipment:**

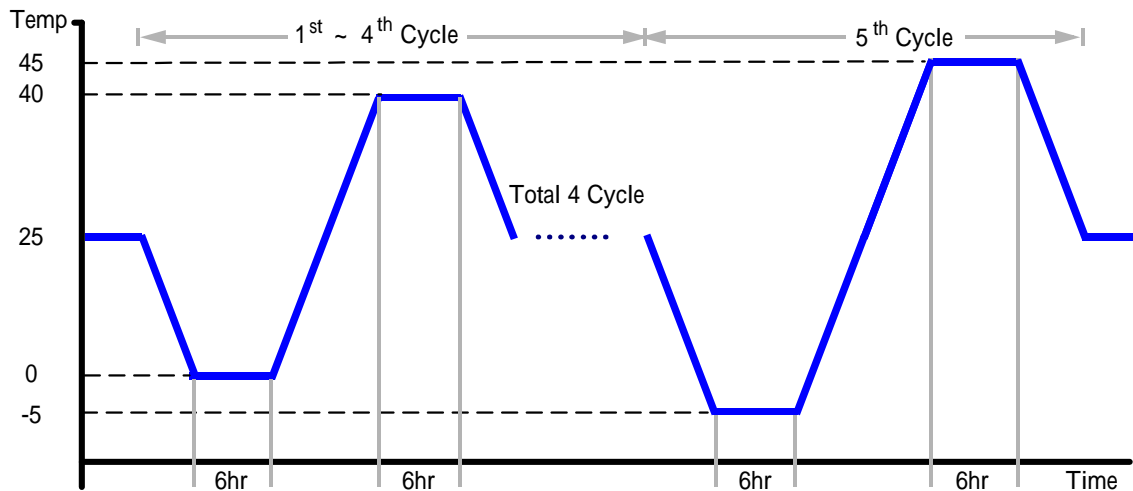
Programmable Temperature & Humidity Chamber  
K.SON. INS. TECH. CORP.  
Model: THS-D4H+-100  
Date of Calibration: 05/24/04  
Serial Number: 1241

**Temperature Measurement:**

20 Channel Thermal Recorder:  
YOKOGAWA Inc,  
Model: DA100-13-1D  
Date of Calibration: 12/25/04  
Serial Number: 12A323190

**Test Condition:**

1. Test Low Temperature: 0 (1~4 cycle)  
-5 (5<sup>th</sup> cycle)
2. Test High Temperature: 40 (1~4 cycle)  
45 (5<sup>th</sup> cycle)
3. Test dwell time: 6Hrs
4. Temperature slope: 2 /min
5. Test cycle: 5 cycle
6. Test Environment Curve:



# Temperature cycle test

Test O.S. / Software:

Windows 2000 / Run PassMark Burn In Test Pro 4.0

Thermal profile data:

## Onyx-153D - Inverter

Point	Temp. Stage( )	Spec	45	40	25	0	-5
1. Inverter - Q2		150	99.6	94.6	79.6	54.6	49.6
2. Inverter - Q4		150	80.8	75.8	60.8	35.8	30.8
3. Inverter - Q6		150	80.4	75.4	60.4	35.4	30.4
4. Inverter - T2		200	78.2	73.2	58.2	33.2	28.2
5. Inverter - Q7		150	77.1	72.1	57.1	32.1	27.1
6. Inverter - Q8		150	76.6	71.6	56.6	31.6	26.6
7. Inverter - IC1		85	67.8	62.8	47.8	22.8	17.8
8. Inverter - SX14		125	74.7	69.7	54.7	29.7	24.7
9. Chamber Air Temperature		N/A	45.3	40.3	25.3	0.3	-4.7

## Onyx-153D - System

Point	Temp. Stage( )	Spec	45	40	25	0	-5
1. Intel Micro-FCBGA 479pin Banias 1.6GHz (PCM-8200 Component Side)		75	82.3	77.3	42.3	2.3	-2.7
2. U12 - CLOCK GENERATOR.ICS.ICS952601 (PCM-8200 Component Side)		100	81.4	76.4	41.4	1.4	-3.6
3. U4 - Intel. RG82855GME (PCM-8200 Component Side)		105	81.4	76.4	41.4	1.4	-3.6
4. U2 - Intel.GD82551ER (PCM-8200 Component Side)		85	79.6	74.6	39.6	-0.4	-5.4
5. Q43 - (PCM-8200 Solder Side)		115	82.3	77.3	42.3	2.3	-2.7
6. Q47 - (PCM-8200 Solder Side)		115	79.1	74.1	39.1	-0.9	-5.9
7. U11 - (Y010 I/O Board A1.0)		130	59.1	54.1	19.1	-20.9	-25.9
8. HDD		55	74.9	69.9	34.9	-5.1	-10.1
9. Memory		70	63.1	58.1	23.1	-16.9	-21.9
10. Control Box. Case Surface		50	49.1	44.1	9.1	-30.9	-35.9
11. Chamber Air Temperature		N/A	48.8	43.8	8.8	-31.2	-36.2

## Onyx-153D - DC Power

Point	Temp. Stage( )	Spec	45	40	25	0	-5
1. L2		130	79.1	74.1	59.1	34.1	29.1
2. L3		130	80.7	75.7	60.7	35.7	30.7
3. T1		130	74.9	69.9	54.9	29.9	24.9
4. T2		130	90.8	85.8	70.8	45.8	40.8
5. Q5		150	79.9	74.9	59.9	34.9	29.9
6. Q1		150	72.4	67.4	52.4	27.4	22.4
7. SCR1		150	102.7	97.7	82.7	57.7	52.7
8. MN1		130	72.8	67.8	52.8	27.8	22.8
9. Chamber Air Temperature		N/A	45.3	40.3	25.3	0.3	-4.7

**Note:** The description in red states which temperature is over the specification of the device.

# Temperature cycle test

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## Sample Configuration & Quantity Under Test:

Quantity: 1 (Onyx-153D)

## Test Result:

The system structure doesn't deformation; Function is passed during system test.

# High temperature storage test

**Test Date:** 10-24~26-2005

**Test Product:** Onyx-153D (PCM-8200 Rev: A1.0).

**Test Site:** AAEON QA Internal Lab.

**Performed By:** Rex Chang

**Test Standard:** Reference IEC 68-2-2 Testing procedures  
Test Bb: Dry Heat Test (Non-operation)

**Test Equipment:**

Programmable Temperature & Humidity Chamber

K.SON. INS. TECH. CORP.

Model: THS-D4L+-100

Date of Calibration: 10/01/04

Serial Number: 2582

**Testing Item:**

1. Test Temperature: 60
2. Test Times: 48Hrs
3. Test Software: Windows media Player (Video test soft-MPEG from HDD)
4. Test Environment Curve:



**Sample Configuration & Quantity Under Test:**

Quantity: 1 (Onyx-153D)

**Test Result:**

The system structure doesn't have any deformation; All functions are passed after high temperature storage test.

# Low temperature storage test

**Test Date:** 10-26~28-2005

**Test Product:** Onyx-153D (PCM-8200 Rev: A1.0).

**Test Site:** AAEON QA Internal Lab.

**Performed By:** Rex Chang

**Test Standard:** Reference IEC 68-2-1  
Testing procedures Test Ab: Cold Test (Non-operation)

**Test Equipment:**  
Programmable Temperature & Humidity Chamber  
K.SON. INS. TECH. CORP.  
Model: THS-D4H+-100  
Date of Calibration: 10/01/04  
Serial Number: 2582

**Testing Item:**

1. Test Temperature: -20
2. Test Times: 48Hrs
3. Test Software: Windows media Player (Video test soft-MPEG from HDD)
4. Test Environment Curve:



**Sample Configuration & Quantity Under Test:**  
Quantity: 1 (Onyx-153D)

**Test Result:**

The system structure doesn't have any deformation; All functions are passed after low temperature storage test.

# Humidity test

**Test Date:** 10-28~31-2005

**Test Product:** Onyx-153D (PCM-8200 Rev: A1.0).

**Test Site:** AAEON QA Internal Lab.

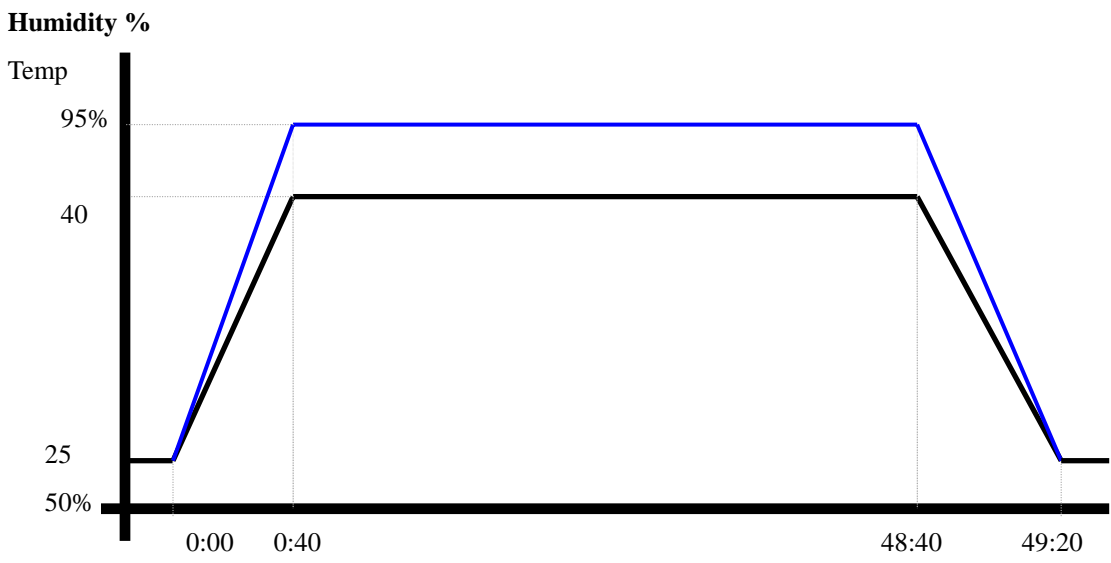
**Performed By:** Rex Chang

**Test Standard:** Reference IEC 68-2-3 Testing procedures  
Test Ca: Damp heat, steady state (Non-operation)

**Test Equipment:**  
Programmable Temperature & Humidity Chamber  
K.SON. INS. TECH. CORP.  
Model: THS-D4H+-100  
Date of Calibration: 10/01/04  
Serial Number: 2582

**Testing Item:**

1. Test Temperature: 40
2. Test Humidity: 95%RH
3. Test Times: 48Hrs
4. Test Software: Windows media Player (Video test soft-MPEG from HDD)
5. Test Environment Curve:



**Sample Configuration & Quantity Under Test:**  
Quantity: 1 (Onyx-153D)

**Test Result:**

The system structure doesn't have any deformation; All functions are passed after humidity test.



# Cold Start test

**Test Date:** 10-31~11/01-2005

**Test Product:** Onyx-153D (PCM-8200 Rev: A1.0).

**Test Site:** AAEON QA Internal Lab.

**Performed By:** Rex Chang

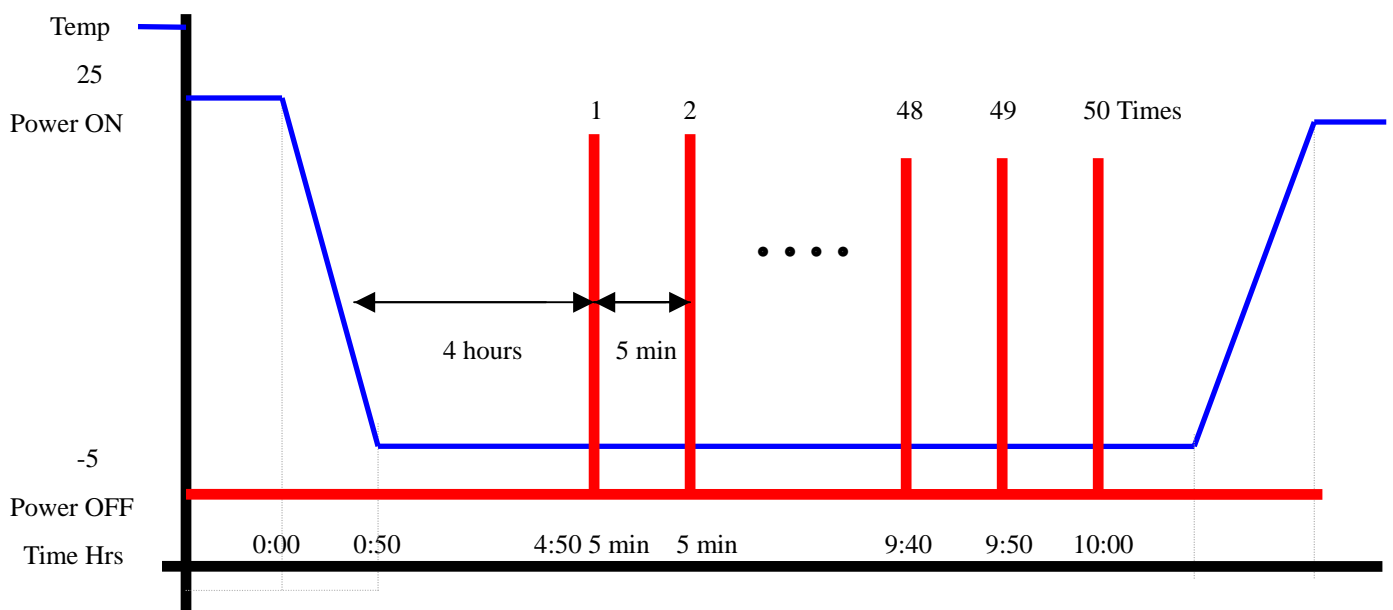
**Test Standard:** Reference IEC 68-2-1 Testing procedures  
Test Ab: Cold Test

**Test Equipment:**

Programmable Temperature & Humidity Chamber  
K.SON. INS. TECH. CORP.  
Model: THS-D4H+-100  
Date of Calibration: 10/01/04  
Serial Number: 2582

**Test Condition:**

1. Test Temperature: -5
2. Test Times: 5 Hours or 50 times of ON/OFF
  - (1) Power off for 4 hours before 1'st power on. Then once complete boot, power off immediately.
  - (2) After 5 min later power on again and wait until booting is completed.
  - (3) Repeat (2) for around 4:50
  - (4) Power off then wait for 5 min before final power on operation.
3. Number of test: 50 times
4. Test Software: Windows 2000
5. Test Environment Curve:



**Sample Configuration & Quantity Under Test:**  
Quantity: 1 (Onyx-153D)

**Test Result:**  
**Passed.**